



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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TC 2800 MAIL ROOM

Application of

Applicants : Chandra V. Mouli and Ceredig Roberts

Serial No. : 09/648,044

Filed : August 25, 2000

Confrm No. : 6800

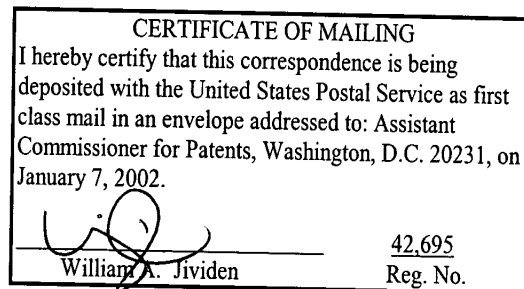
Title : **METHOD AND DEVICE TO REDUCE GATE-INDUCED DRAIN  
LEAKAGE (GIDL) CURRENT IN THIN GATE OXIDE MOSFETs**

Docket No. : MIO 0054 PA

Examiner : O. Nadav

Art Unit : 2811

Assistant Commissioner for Patents  
Washington, D.C. 20231



Sir:

AMENDMENT

This paper is being filed in response to the Office Action mailed December 5, 2001, thereby having a non-fee response date of no later than March 5, 2002.

Reconsideration and reexamination are respectfully requested in light of the amendments and remarks below.

In the Drawing

The Applicant encloses herewith new FIG. 3E illustrating the subject matter described in the specification and claims of the present application for approval by the examiner. It is respectfully submitted that the presently proposed figure drawing more accurately illustrate the recited subject matter of the present invention. No new matter has been entered.

In the Specification

Attached hereto as Appendix A is a marked up reproduction of the changes made to the specification and claims by the current amendments. Additions have been underscored and deletions have been stricken.